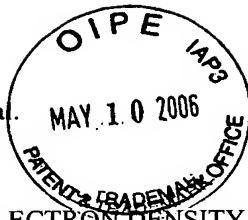


Docket No. 262790US6YA PCT  
IN RE APPLICATION OF: Eric J. STRANG, et al.  
SERIAL NO: 10/521,118  
FILED: January 12, 2005  
FOR: METHOD AND SYSTEM FOR ELECTRON DENSITY MEASUREMENT



DFW

COMMISSIONER FOR PATENTS  
ALEXANDRIA, VIRGINIA 22313

SIR:  
Transmitted herewith is an amendment under 37 C.F.R. § 1.111 in the above-identified application.

- ☒ No additional fee is required
- ☐ Small entity status of this application under 37 C.F.R. §1.9 and §1.27 is claimed.
- ☒ Additional documents filed herewith: Letter Submitting Replacement Drawing Sheet(s); Replacement Drawing (1 sheet)

The Fee has been calculated as shown below:

CLAIMS	CLAIMS REMAINING		HIGHEST NUMBER PREVIOUSLY PAID	NO. EXTRA CLAIMS	RATE	CALCULATIONS
TOTAL	42	MINUS	42	0	x \$50 =	\$0.00
INDEPENDENT	6	MINUS	6	0	x \$200 =	\$0.00
APPLICATION SIZE		MINUS	100	0 (each addtl. 50 sheets)	x \$250 =	\$0.00
		<input type="checkbox"/> MULTIPLE DEPENDENT CLAIMS			+ \$360 =	\$0.00
		TOTAL OF ABOVE CALCULATIONS				\$0.00
		<input type="checkbox"/> Reduction by 50% for filing by Small Entity				\$0.00
		TOTAL				\$0.00

- ☐ A check in the amount of \$0.00 is attached.
- ☐ Credit card payment form is attached to cover the fees in the amount of \$0.00
- ☒ Please charge any additional Fees for the papers being filed herewith and for which no check or credit card payment is enclosed herewith, or credit any overpayment to deposit Account No. 15-0030. A duplicate copy of this sheet is enclosed.
- ☒ If these papers are not considered timely filed by the Patent and Trademark Office, then a petition is hereby made under 37 C.F.R. §1.136, and any additional fees required under 37 C.F.R. §1.136 for any necessary extension of time may be charged to Deposit Account No. 15-0030. A duplicate copy of this sheet is enclosed.

OBLON, SPIVAK, McCLELLAND,  
MAIER & NEUSTADT, P.C.

*R Fetea*

Steven P. Weihrouch  
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Docket No. 262790US6YA PCT



IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

IN RE APPLICATION: Eric J. STRANG, et al.

SERIAL NO.: 10/521,118

GAU: 2857

FILED: January 12, 2005

EXAMINER: BARBEE, M. L.

FOR: METHOD AND SYSTEM FOR ELECTRON DENSITY MEASUREMENT

**LETTER SUBMITTING REPLACEMENT DRAWING SHEET(S)**

COMMISSIONER FOR PATENTS  
Alexandria, VA 22313

SIR:

Responsive to the below indicated communication, the following drawing sheet is submitted herewith:

☒ 1 Replacement Drawing Sheet ☐ \_\_\_\_\_ New Drawing Sheets

☒ Official Action dated February 10, 2006

☐ Notice of Allowance/Issue Fee dated \_\_\_\_\_

☐ Other dated \_\_\_\_\_

The changes and/or modifications made include the following:

Figure 1 includes reference sign 30, which replaced reference sign 10.

Respectfully Submitted,

OBLON, SPIVAK, McCLELLAND,  
MAIER & NEUSTADT, P.C.

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